

40V COMPLEMENTARY DUAL ENHANCEMENT MODE MOSFET

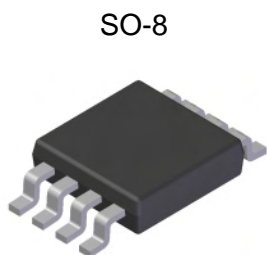
Product Summary

Device	V _{(BR)DSS}	R _{DS(on)} Max	I _D T _A = 25°C
Q1	40V	28mΩ @ V _{GS} = 10V	7.2A
		49mΩ @ V _{GS} = 4.5V	5.4A
Q2	-40V	50mΩ @ V _{GS} = -10V	-5.2A
		79mΩ @ V _{GS} = -4.5V	-4.7A

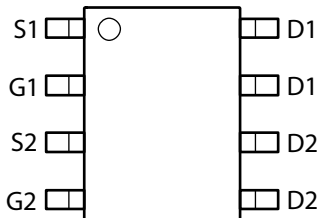
Description and Applications

This MOSFET has been designed to minimize the on-state resistance and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

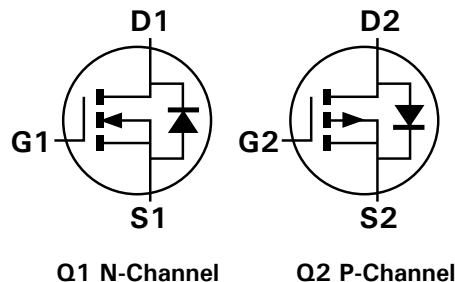
- Motor control
- Backlighting
- DC-DC Converters
- Power management functions



Top View



Top View



Equivalent Circuit

Features and Benefits

- Low on-resistance
- Fast switching speed
- "Lead Free", RoHS Compliant (Note 1)
- Halogen and Antimony Free "Green" Device (Note 2)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

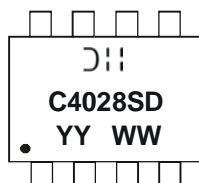
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0 (Note 1)
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See diagram below
- Terminals: Finish - Matte Tin annealed over Copper lead frame. Solderable per MIL-STD-202, Method 208
- Weight: 0.074 grams (approximate)

Ordering Information (Note 3)

Product	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
DMC4028SSD-13	C4028SD	13	12	2,500

- Notes:
1. No purposefully added lead.
 2. Diodes Inc.'s "Green" policy can be found on our website at <http://www.diodes.com>.
 3. For packaging details, go to our website at <http://www.diodes.com>.

Marking Information



011 = Manufacturer's Marking
 C4028SD = Product Type Marking Code
 YYWW = Date Code Marking
 YY = Year (ex: 09 = 2009)
 WW = Week (01 - 53)

Maximum Ratings @T_A = 25°C unless otherwise specified

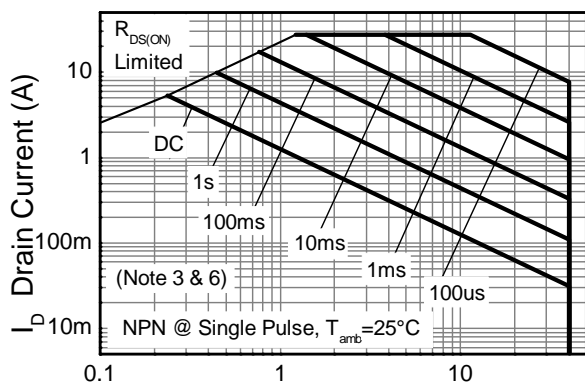
Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			V _{DSS}	40	-40	V
Gate-Source Voltage			V _{GSS}	±20	±20	V
Continuous Drain Current	V _{GS} = 10V	(Note 4)	I _D	7.2	5.2	A
		(Notes 6 & 8)		5.5	4.2	
		T _A = 70°C (Notes 6 & 8)		5.4	4	
		(Notes 5 & 8)		6.5	4.8	
Pulsed Drain Current	V _{GS} = 10V	(Notes 7 & 8)	I _{DM}	27.3	20.4	A
Continuous Source Current (Body diode)			I _S	3.35	3.15	A
Pulsed Source Current (Body diode)			I _{SM}	27.3	20.4	A

Thermal Characteristics @T_A = 25°C unless otherwise specified

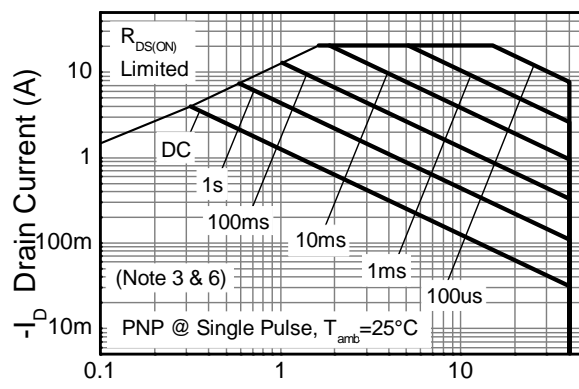
Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Unit
Power Dissipation Linear Derating Factor	(Notes 5 & 8)	P _D	1.25		W mW/°C
	(Notes 5 & 9)		10		
	(Notes 6 & 8)		1.8		
	(Notes 5 & 8)		14.3		
Thermal Resistance, Junction to Ambient	(Notes 5 & 8)	R _{θJA}	2.16		°C/W
	(Notes 5 & 9)		17.2		
	(Notes 6 & 8)		100		
Thermal Resistance, Junction to Lead	(Notes 5 & 8)	R _{θJL}	70		°C/W
	(Notes 5 & 9)		58		
	(Notes 6 & 8)		53	53	
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150		°C

- Notes:
- AEC-Q101 V_{GS} maximum is ±16V.
 - For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
 - Same as note (5), except the device is measured at t ≤ 10 sec.
 - Same as note (5), except the device is pulsed with D= 0.02 and pulse width 300 μs. The pulse current is limited by the maximum junction temperature.
 - For a dual device with one active die.
 - For a device with two active die running at equal power.
 - Thermal resistance from junction to solder-point (at the end of the drain lead).

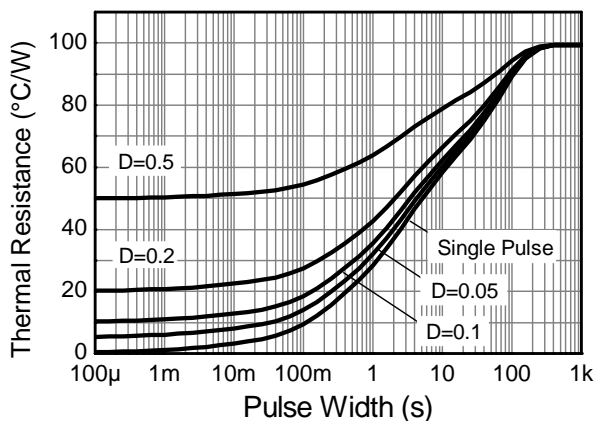
Thermal Characteristics



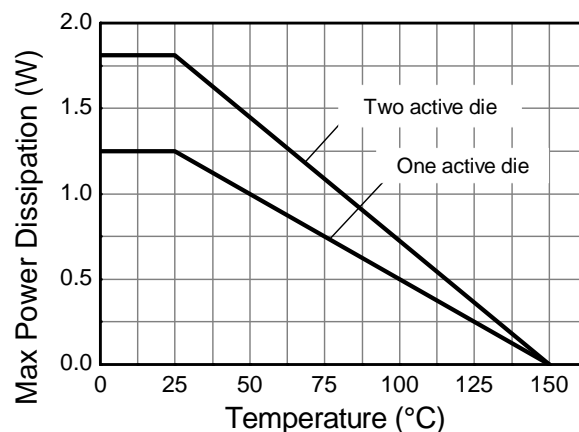
N-channel Safe Operating Area



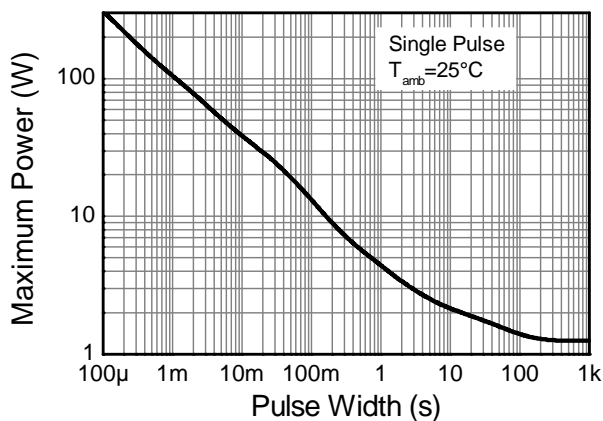
P-channel Safe Operating Area



Transient Thermal Impedance



Derating Curve



Pulse Power Dissipation

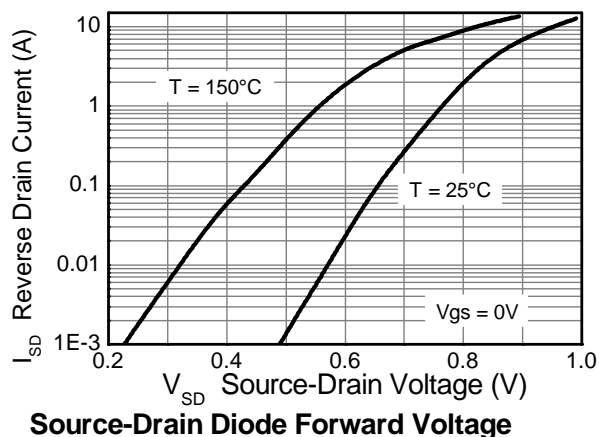
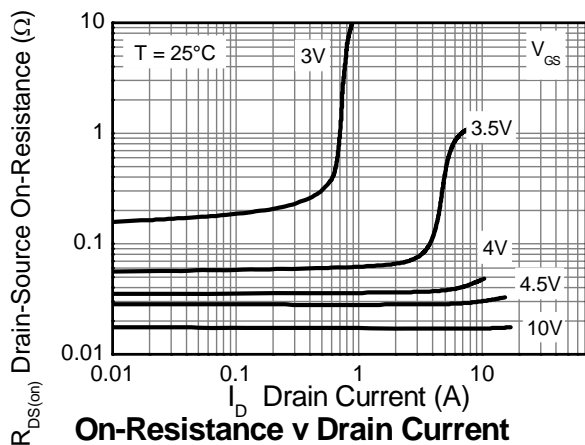
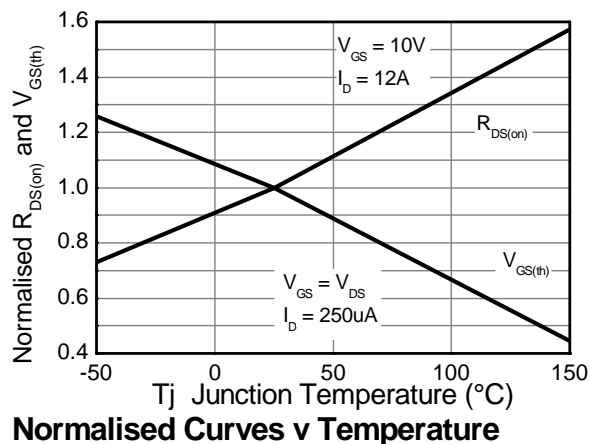
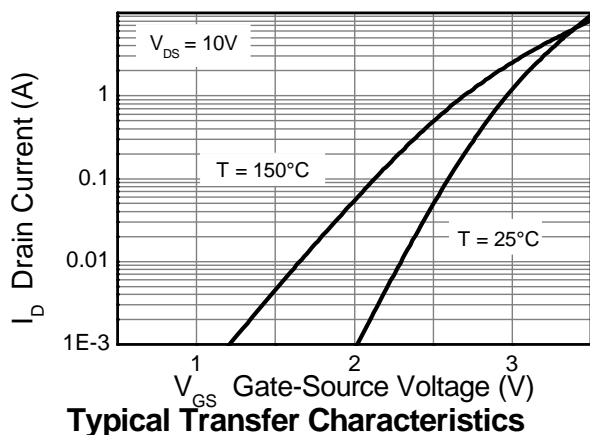
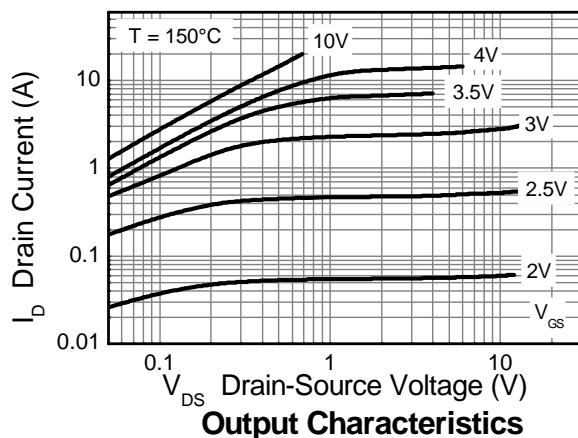
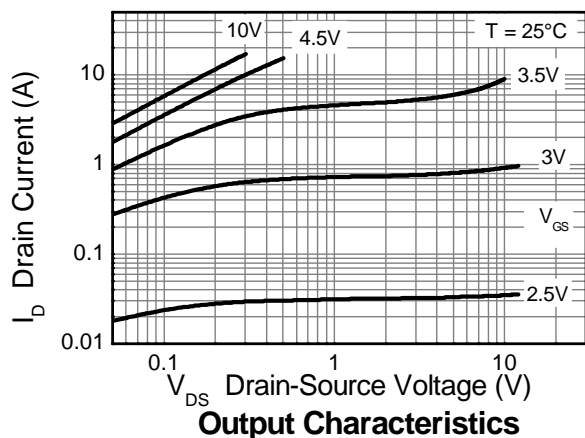
Electrical Characteristics – Q1 N-Channel

 $T_A = 25^\circ\text{C}$ unless otherwise specified

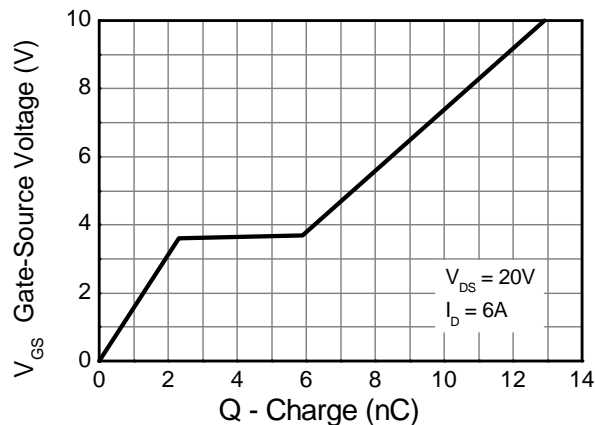
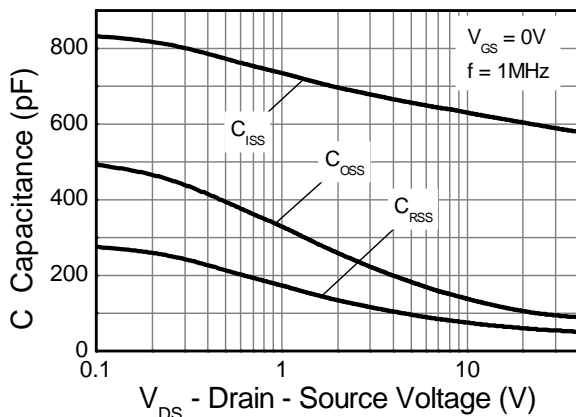
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	40	—	—	V	I _D = 250μA, V _{GS} = 0V	
Zero Gate Voltage Drain Current	I _{DSS}	—	—	0.5	μA	V _{DS} = 40V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	1.0	—	3.0	V	I _D = 250μA, V _{DS} = V _{GS}	
Static Drain-Source On-Resistance (Note 11)	R _{DS (ON)}	—	0.018	0.028	Ω	V _{GS} = 10V, I _D = 6A	
			0.033	0.049		V _{GS} = 4.5V, I _D = 5A	
Forward Transconductance (Notes 11 & 12)	g _{fs}	—	22.8	—	S	V _{DS} = 15V, I _D = 6A	
Diode Forward Voltage (Note 11)	V _{SD}	—	0.845	1.1	V	I _S = 6A, V _{GS} = 0V	
Reverse recovery time (Note 12)	t _{rr}	—	135	—	ns	I _S = 6A, di/dt = 100A/μs	
Reverse recovery charge (Note 12)	Q _{rr}	—	799	—	nC		
DYNAMIC CHARACTERISTICS (Note 12)							
Input Capacitance	C _{iss}	—	604	—	pF	V _{DS} = 20V, V _{GS} = 0V f = 1MHz	
Output Capacitance	C _{oss}	—	106	—	pF		
Reverse Transfer Capacitance	C _{rss}	—	59.6	—	pF		
Total Gate Charge (Note 13)	Q _g	—	6.5	—	nC	V _{GS} = 4.5V	V _{DS} = 20V I _D = 6A
Total Gate Charge (Note 13)	Q _g	—	12.9	—	nC	V _{GS} = 10V	
Gate-Source Charge (Note 13)	Q _{gs}	—	2.3	—	nC		
Gate-Drain Charge (Note 13)	Q _{gd}	—	3.6	—	nC		
Turn-On Delay Time (Note 13)	t _{D(on)}	—	4.2	—	ns	V _{DD} = 20V, V _{GS} = 10V I _D = 6A, R _G ≅ 6.0Ω	
Turn-On Rise Time (Note 13)	t _r	—	12.4	—	ns		
Turn-Off Delay Time (Note 13)	t _{D(off)}	—	13.8	—	ns		
Turn-Off Fall Time (Note 13)	t _f	—	10.7	—	ns		

Notes: 11. Measured under pulsed conditions. Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$
12. For design aid only, not subject to production testing.
13. Switching characteristics are independent of operating junction temperatures.

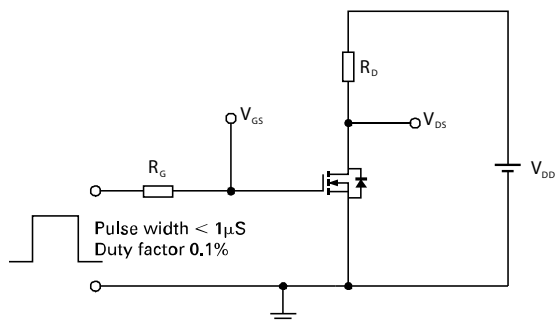
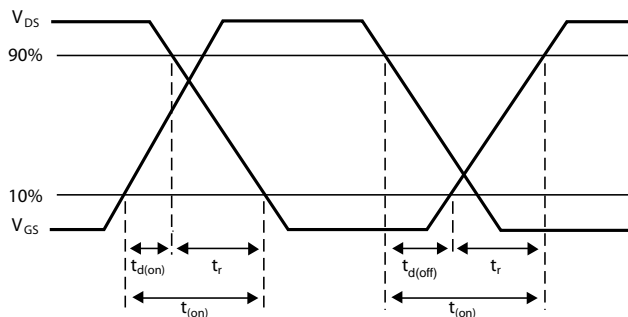
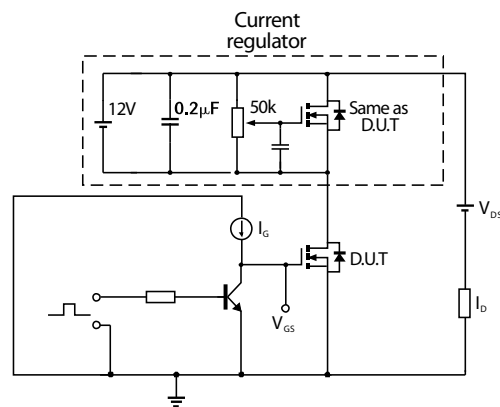
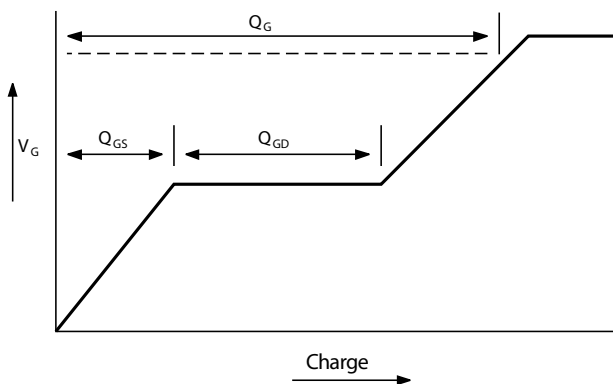
Typical Characteristics – Q1 N-Channel



Typical Characteristics – Q1 N-Channel - continued



Test Circuits – Q1 N-Channel

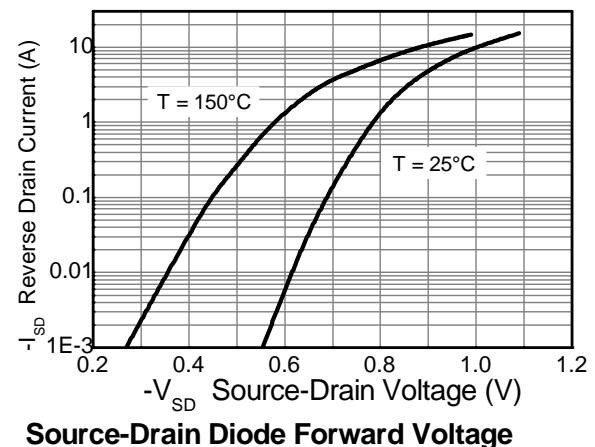
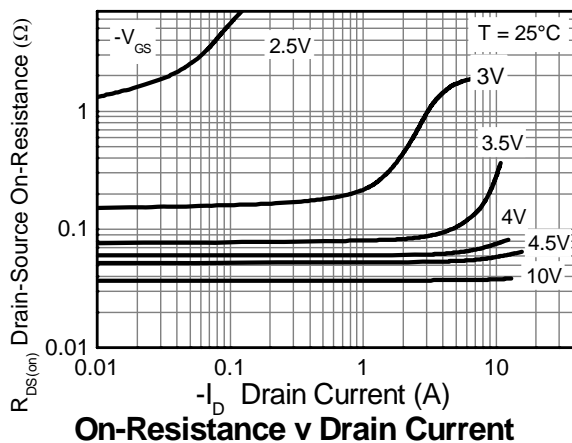
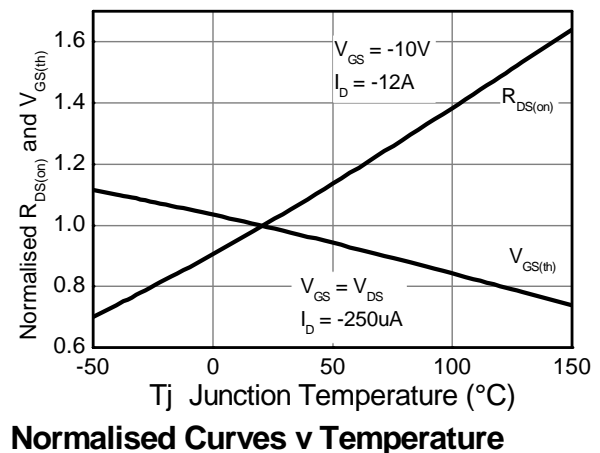
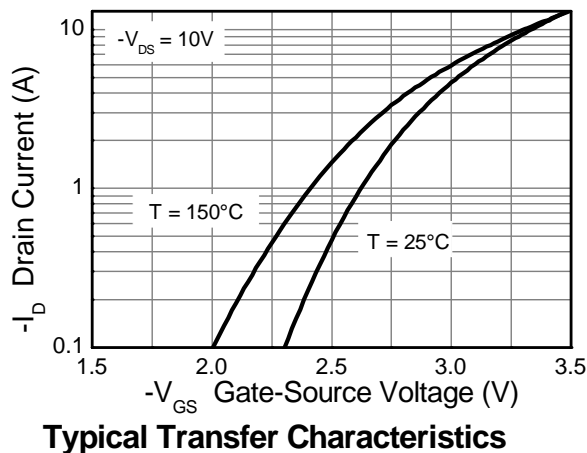
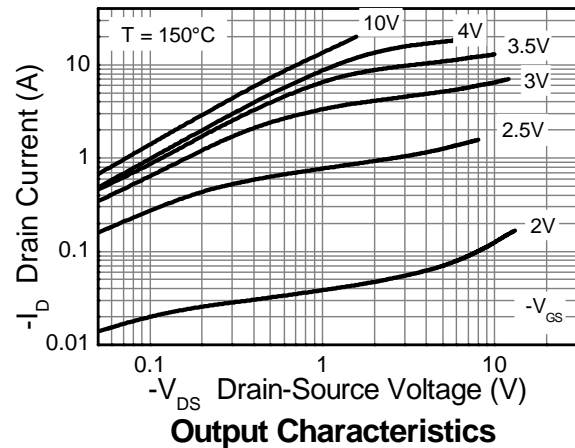
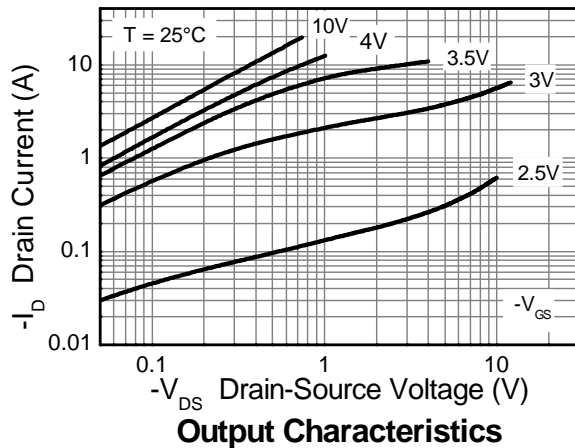


Electrical Characteristics – Q2 P-Channel @T_A = 25°C unless otherwise specified

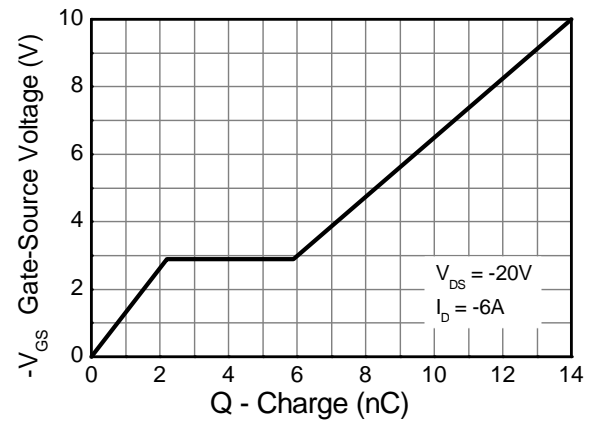
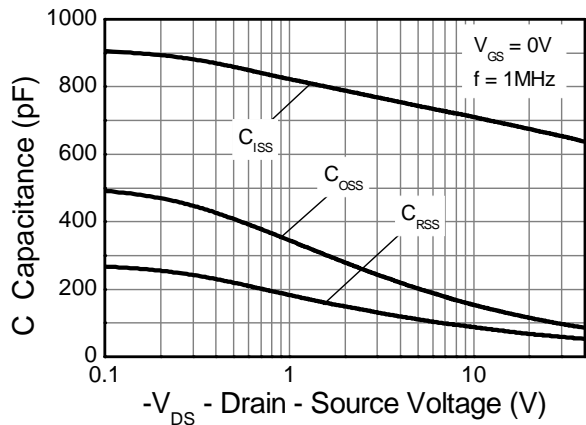
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	-40	—	—	V	I _D = -250μA, V _{GS} = 0V	
Zero Gate Voltage Drain Current	I _{DSS}	—	—	-0.5	A	V _{DS} = -40V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	-1.0	—	-3.0	V	I _D = -250μA, V _{DS} = V _{GS}	
Static Drain-Source On-Resistance (Note 14)	R _{DS (ON)}	—	0.039	0.050	Ω	V _{GS} = -10V, I _D = -6A	
			0.060	0.079		V _{GS} = -4.5V, I _D = -5A	
Forward Transconductance (Notes 14 & 15)	g _{fs}	—	16.6	—	S	V _{DS} = -15V, I _D = -6A	
Diode Forward Voltage (Note 4)	V _{SD}	—	-0.865	-1.1	V	I _S = -6A, V _{GS} = 0V	
Reverse recovery time (Note 15)	t _{rr}	—	138	—	ns	I _S = -6A, di/dt = 100A/μs	
Reverse recovery charge (Note 15)	Q _{rr}	—	841	—	nC		
DYNAMIC CHARACTERISTICS (Note 15)							
Input Capacitance	C _{iss}	—	674	—	pF	V _{DS} = -20V, V _{GS} = 0V f = 1MHz	
Output Capacitance	C _{oss}	—	115	—	pF		
Reverse Transfer Capacitance	C _{rss}	—	67.7	—	pF		
Total Gate Charge (Note 16)	Q _g	—	7.0	—	nC	V _{GS} = -4.5V	V _{DS} = -20V I _D = -6A
Total Gate Charge (Note 16)	Q _g	—	14	—	nC	V _{GS} = -10V	
Gate-Source Charge (Note 16)	Q _{gs}	—	2.2	—	nC		
Gate-Drain Charge (Note 16)	Q _{gd}	—	3.7	—	nC		
Turn-On Delay Time (Note 16)	t _{D(on)}	—	2.3	—	ns	V _{DD} = -20V, V _{GS} = -10V I _D = -6A, R _G ≅ 6.0Ω	
Turn-On Rise Time (Note 16)	t _r	—	14.1	—	ns		
Turn-Off Delay Time (Note 16)	t _{D(off)}	—	25.1	—	ns		
Turn-Off Fall Time (Note 16)	t _f	—	14.3	—	ns		

Notes: 14. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%
15. For design aid only, not subject to production testing.
16. Switching characteristics are independent of operating junction temperatures.

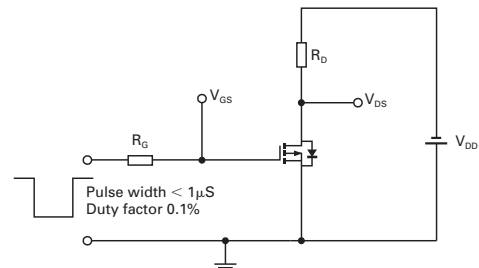
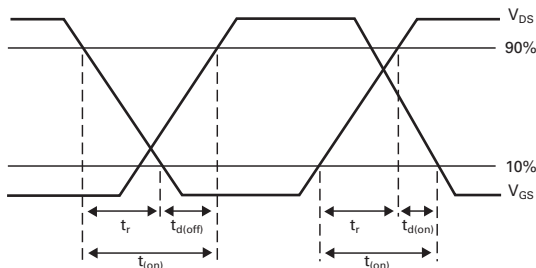
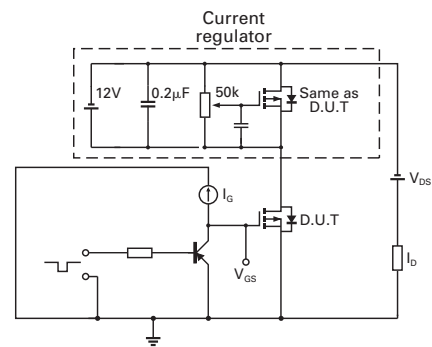
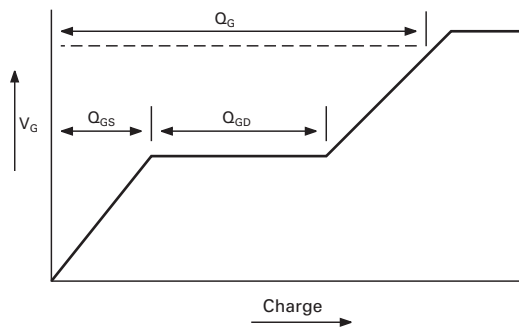
Typical Characteristics – Q2 P-Channel



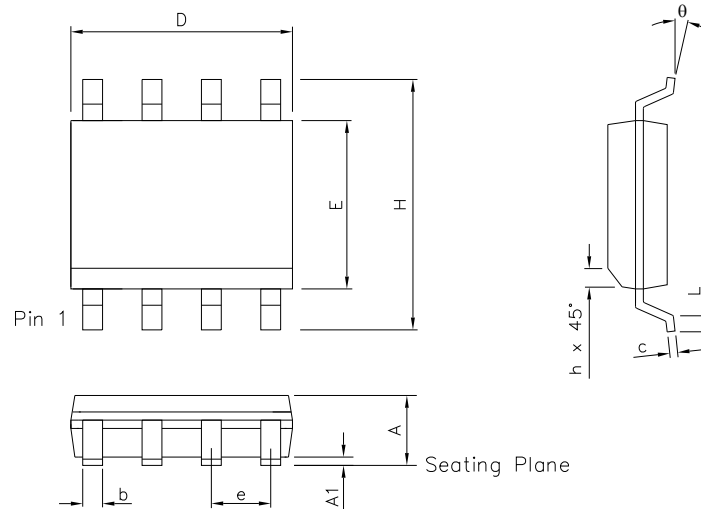
Typical Characteristics – Q2 P-Channel - continued



Test Circuits – Q2 P-Channel

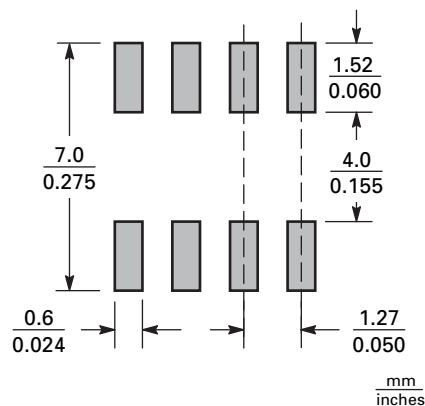


Package Outline Dimensions



DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.053	0.069	1.35	1.75	e	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	c	0.008	0.010	0.19	0.25
H	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Suggested Pad Layout



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2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.

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